Product/Process Change Notice - PCN 19_0147 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADG5208F Family Die Revision

Publication Date: 01-Feb-2021

Effectivity Date: 06-May-2021 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:
Initial Release

Description Of Change:

Metal 2 edit to remove some circuits that are causing yield loss.
5 Generics are covered by this change ADG5208F, ADG5209F, ADG5243F, ADG5248F, ADG5249F

ESD ratings for all 5 generics have been affected, see attachments for qual results summary.

The ADG5243F datasheet Specification for Drain off leakage with overvoltage has been affected, See attachments for full change details.

Reason For Change:

Yield Improvement

Impact of the change (positive or negative) on fit, form, function & reliability:

There will be no impact on form, fit, function, quality or reliability of the product. ESD & Leakage Specs will change as outlined.

Product Identification *(this section will describe how to identify the changed material)*

Changed ADG5208F material is identified by Date code 1945 and newer.

Changed ADG5243F material is identified by Date code 2022 and newer.
The ADG5243F specification changes will be outlined in Rev B of the ADG5243F datasheet.

Date codes for the remaining generics ADG5209F, ADG5248F & ADG5249F will be advised when available in a later revision of this PCN.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Datasheet Specification Comparison

ADI_PCN_19_0147_Rev_-_ADG5243F Datasheet PCN comparison.pdf

Attachment 2: Type: Qualification Results Summary

ADI_PCN_19_0147_Rev_-_ESD Qual Results Summary.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.			
Americas: PCN_Americas@analog.com	**Europe:** PCN_Europe@analog.com	**Japan:** PCN_Japan@analog.com	**Rest of Asia:** PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (15)				
ADG5208F / ADG5208FBCPZ-RL7	ADG5208F / ADG5208FBRUZ	ADG5208F / ADG5208FBRUZ-RL7	ADG5209F / ADG5209FBCPZ-RL7	ADG5209F / ADG5209FBRUZ
ADG5209F / ADG5209FBRUZ-RL7	ADG5243F / ADG5243FBCPZ-RL7	ADG5243F / ADG5243FBRUZ	ADG5243F / ADG5243FBRUZ-RL7	ADG5248F / ADG5248FBCPZ-RL7
ADG5248F / ADG5248FBRUZ	ADG5248F / ADG5248FBRUZ-RL7	ADG5249F / ADG5249FBCPZ-RL7	ADG5249F / ADG5249FBRUZ	ADG5249F / ADG5249FBRUZ-RL7

Appendix B - Revision History			
Rev	**Publish Date**	**Effectivity Date**	**Rev Description**
Rev. -	01-Feb-2021	06-May-2021	Initial Release

Table 4: ADG5208F ESD Test Results

ESD Model	Package	ESD Test Spec	RC Network	Highest Pass Level	First Fail Level	Class
FICDM	16-TSSOP_4.4	JS-002	1Ω, Cpkg	±500V	±750V	C2a
HBM	16-TSSOP_4.4	JESD22-A114	1.5kΩ, 100pF	±2000V	±2500V	2

REV A DATASHEET

±20 V DUAL SUPPLY

V_{DD} = 20 V ± 10%, V_{SS} = −20 V ± 10%, GND = 0 V, $C_{DECOUPLING}$ = 0.1 µF, unless otherwise noted.

Table 1.

	Rev. A					Rev.B			
Parameter	**+25°C**	**−40°C to +85°C**	**−40°C to +125°C**	**Unit**		**+25°C**	**−40°C to +85°C**	**−40°C to +125°C**	**Unit**
FAULT									
Source Leakage Current, I_S									
With Overvoltage	±66			µA typ		±66			µA typ
Power Supplies Grounded or Floating	±25			µA typ		±25			µA typ
Drain Leakage Current, I_D									
With Overvoltage	±2			nA typ		±2			nA typ
	±8	±15	±50	nA max		±2	±2	±2	µA max
Power Supplies Grounded	±5			nA typ		±5			nA typ
	±100	±100	±100	nA max		±100	±100	±100	nA max
Power Supplies Floating	±50	±50	±50	µA typ		±50	±50	±50	µA typ